



FOR IMMEDIATE RELEASE

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**AEHR TEST SYSTEMS ANNOUNCES \$2 MILLION IN ORDERS FROM  
AUTOMOTIVE IC MANUFACTURERS**

**Fremont, CA (November 26, 2012) - Aehr Test Systems (Nasdaq: AEHR)**, a worldwide supplier of semiconductor test and burn-in equipment, today announced it has received over \$2 million in follow-on production orders for its burn-in and test systems from multiple leading manufacturers of advanced logic integrated circuits (ICs) for automotive applications.

“The follow-on orders show that the burn-in and test process using Aehr Test’s systems are cost effective for reliability screening of a wide range of ICs for the automotive market,” said Carl Buck, vice president of marketing at Aehr Test Systems. “ICs used by the auto manufacturers need to meet strict quality and reliability standards. Burn-in screening is an essential process for meeting the ‘zero parts per million’ failure rate required by leading auto manufacturers.

“The burn-in process is used both for production for complex devices and for qualification for virtually all new automotive ICs,” Buck continued. “A typical HTOL (high temperature operating life) qualification stresses several hundred devices at 125C to 150C for 1000 hours.”

According to IC Insights, a leading semiconductor research company, IC usage for automotive applications including engine control, navigation, infotainment, communications, battery management and sensors is projected to outpace the total IC market and have a compound annual growth rate over 20% greater than the IC market as a whole for the next 5 years.

“We are seeing increasing capacity needs for our ABTS™ products in both production burn-in and device qualifications due to the growth in the automotive and mobility markets,” Buck concluded.

The ABTS family of products is based on a new hardware and software platform that is designed to address not only today’s devices, but also future devices for many years to come. It can test and burn-in both logic and memory devices, including resources for high pin-count devices and configurations for high-power and low-power applications. The ABTS system can be configured with up to 72 burn-in boards with up to 320 I/O channels each and 32M of test vector memory per channel. The ABTS system is optimized for use with the Sensata iSocket\* Thermal Management Technology, which provides a scalable cost-effective solution using individual device temperature control for ICs up to 75 watts or more. Individual temperature control enables high-power devices with a broad range of power dissipation to be burned-in

simultaneously in a single burn-in chamber while maintaining a precise device temperature. The ABTS system also uses N+1 redundancy technology for many key components in the system to maximize system uptime.

\*iSocket is a trademark of Sensata Technologies, Inc.

### **About Aehr Test Systems**

Headquartered in Fremont, California, Aehr Test Systems is a worldwide provider of test systems for burning-in and testing logic and memory integrated circuits and has an installed base of more than 2,500 systems worldwide. Increased quality and reliability needs of the Automotive and Mobility integrated circuit markets are driving additional test requirements, capacity needs and opportunities for Aehr Test products in package and wafer level test. Aehr Test has developed and introduced several innovative products, including the ABTS and FOX™ families of test and burn-in systems and the DiePak® carrier. The ABTS system is used in production and qualification testing of packaged parts for both low-power and high-power logic as well as all common types of memory devices. The FOX system is a full wafer contact test and burn-in system used for burn-in and functional test of complex devices, such as leading-edge memories, digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The DiePak carrier is a reusable, temporary package that enables IC manufacturers to perform cost-effective final test and burn-in of bare die. For more information, please visit the Company's website at [www.aehr.com](http://www.aehr.com).

### **Safe Harbor Statement**

This release contains forward-looking statements that involve risks and uncertainties relating to projections regarding customer demand and acceptance of Aehr Test's products. Actual results may vary from projected results. These risks and uncertainties include, without limitation, acceptance by customers of the ABTS technology, acceptance by customers of the ABTS systems shipped upon receipt of a purchase order and the ability of new products to meet customer needs or perform as described. See Aehr Test's recent 10-K, 10-Q and other reports from time to time filed with the Securities and Exchange Commission for a more detailed description of the risks facing our business. The Company disclaims any obligation to update information contained in any forward-looking statement to reflect events or circumstances occurring after the date of this press release.

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